

Abstract Submitted
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Electrical field induced Metal-Insulator Transition in NbO₂ thin films at room temperature YUHAN WANG, STUART WOLF, JIWEI LU, Univ of Virginia — Highly correlated oxides that exhibit a metal to insulator transition (MIT) are of great interest because of their potential application to high performance switches. NbO₂ exhibits a MIT at 1081K accompanied by a structural transformation from rutile to a distorted variant, which makes it a potential candidate for the switching applications. By a reactive bias target ion beam deposition (RBTIBD) growth technique, we have obtained crystalline single phase NbO₂ thin films grown on Al₂O₃ (0001), Au/Al₂O₃(0001), and Pt/Al₂O₃(0001) substrates. AFM, XRD and Raman spectroscopy were used to characterize the morphology and microstructure of the NbO₂ films. We have observed electrically induced transitions from the insulating to the metallic state with two orders of magnitude change in the resistivity at room temperature. This transition occurred at an electric field between 30-100 kV/cm. We will discuss the possible mechanisms for this induced MIT.

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